

Search Notes

Application/Control No.

10/532,632

Examiner

Emmanuel Bayard

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	299	1/31/2007	EB
375	267	1/31/2007	EB
375	150	1/31/2007	EB
375	349	1/31/2007	EB
375	347	1/31/2007	EB
375	295	1/31/2007	EB
370	335	1/31/2007	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	1/31/2007	EB